

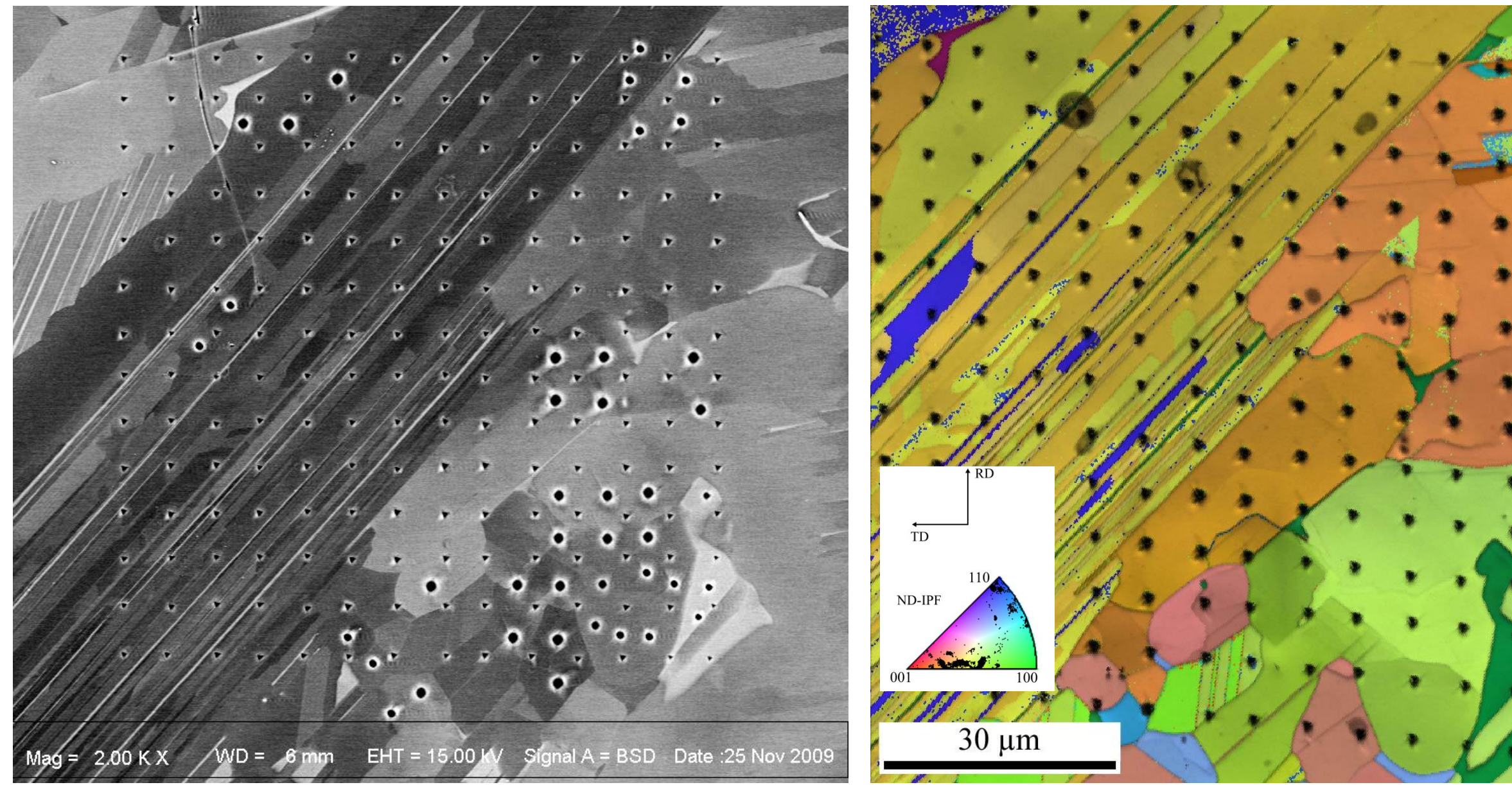
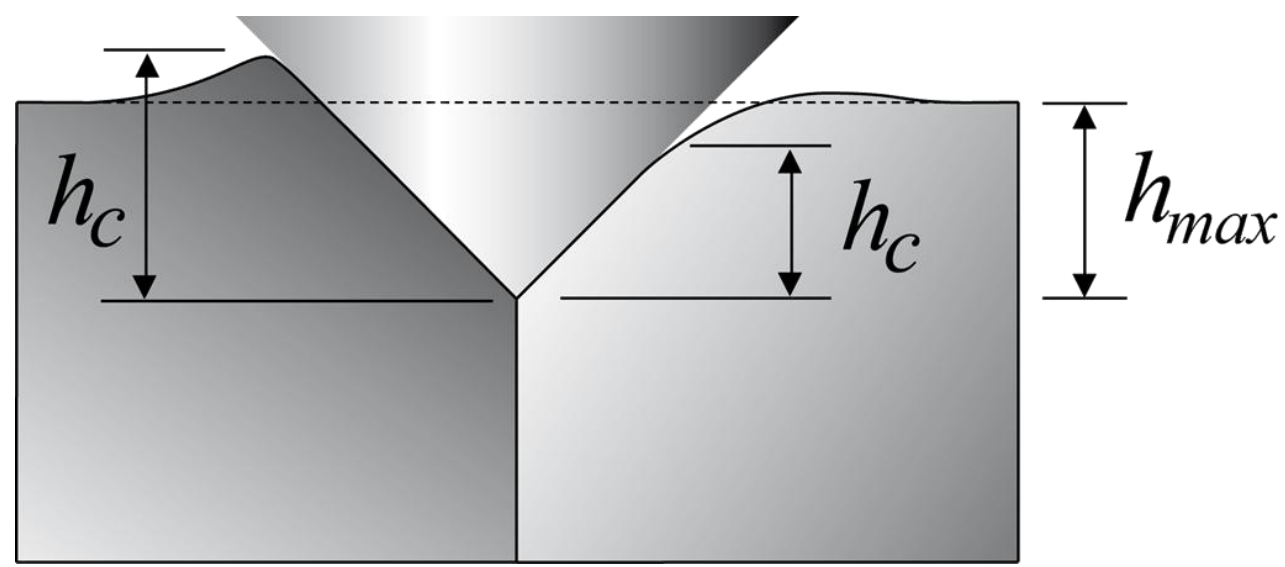
Analysis of Deformation Mechanisms in Gamma-TiAl by Nanoindentation Experiments and Crystal Plasticity Simulations

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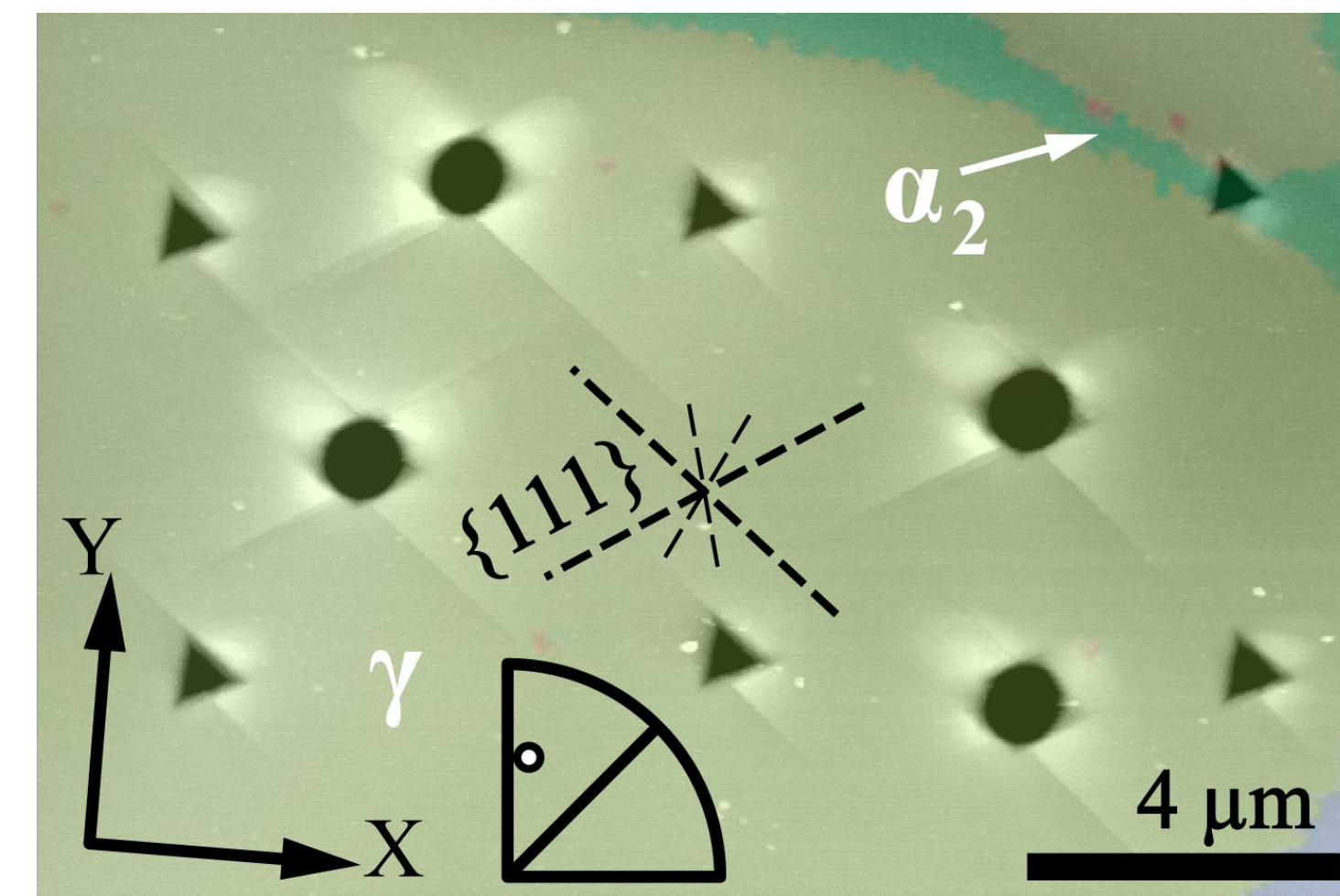


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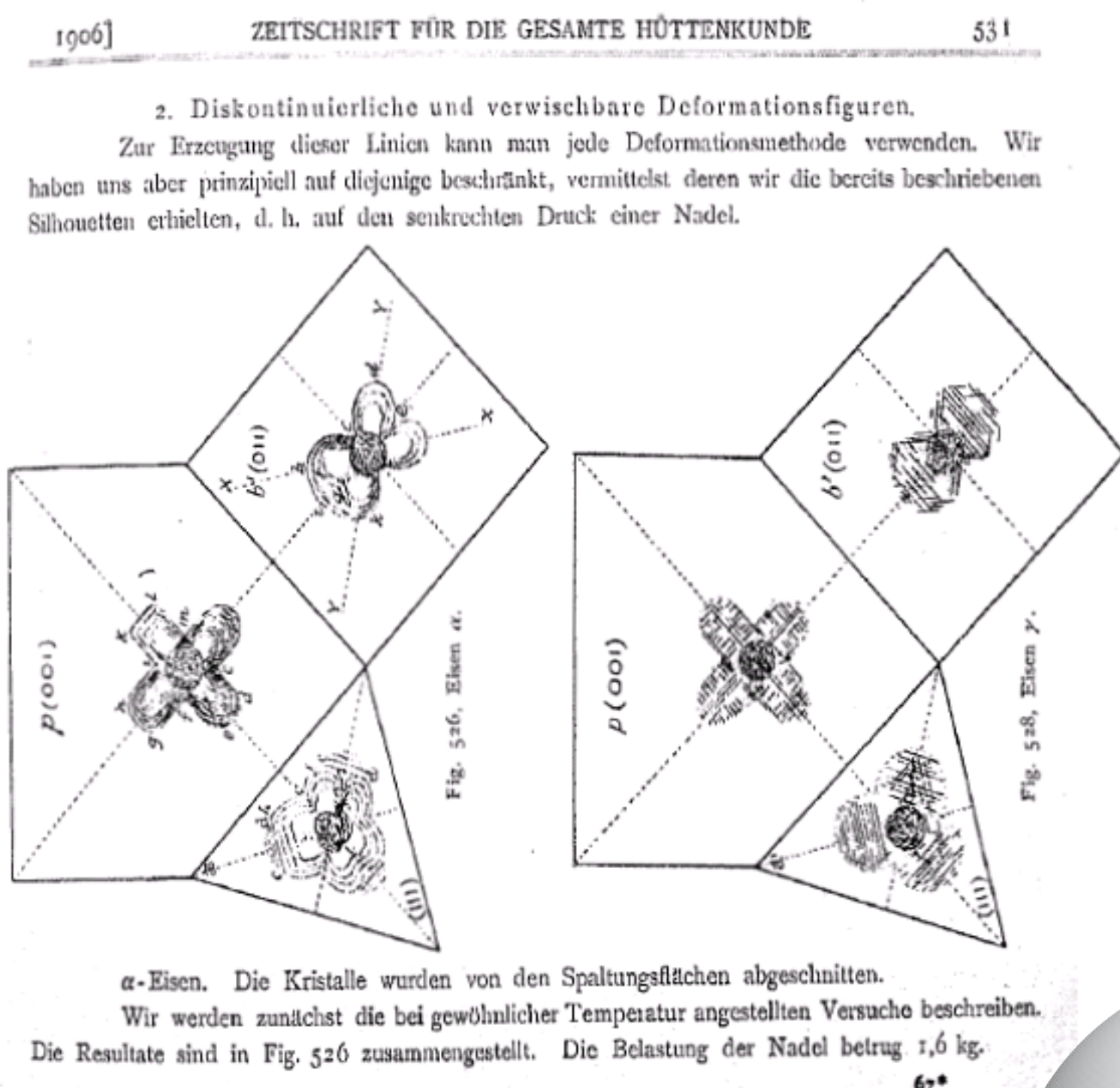
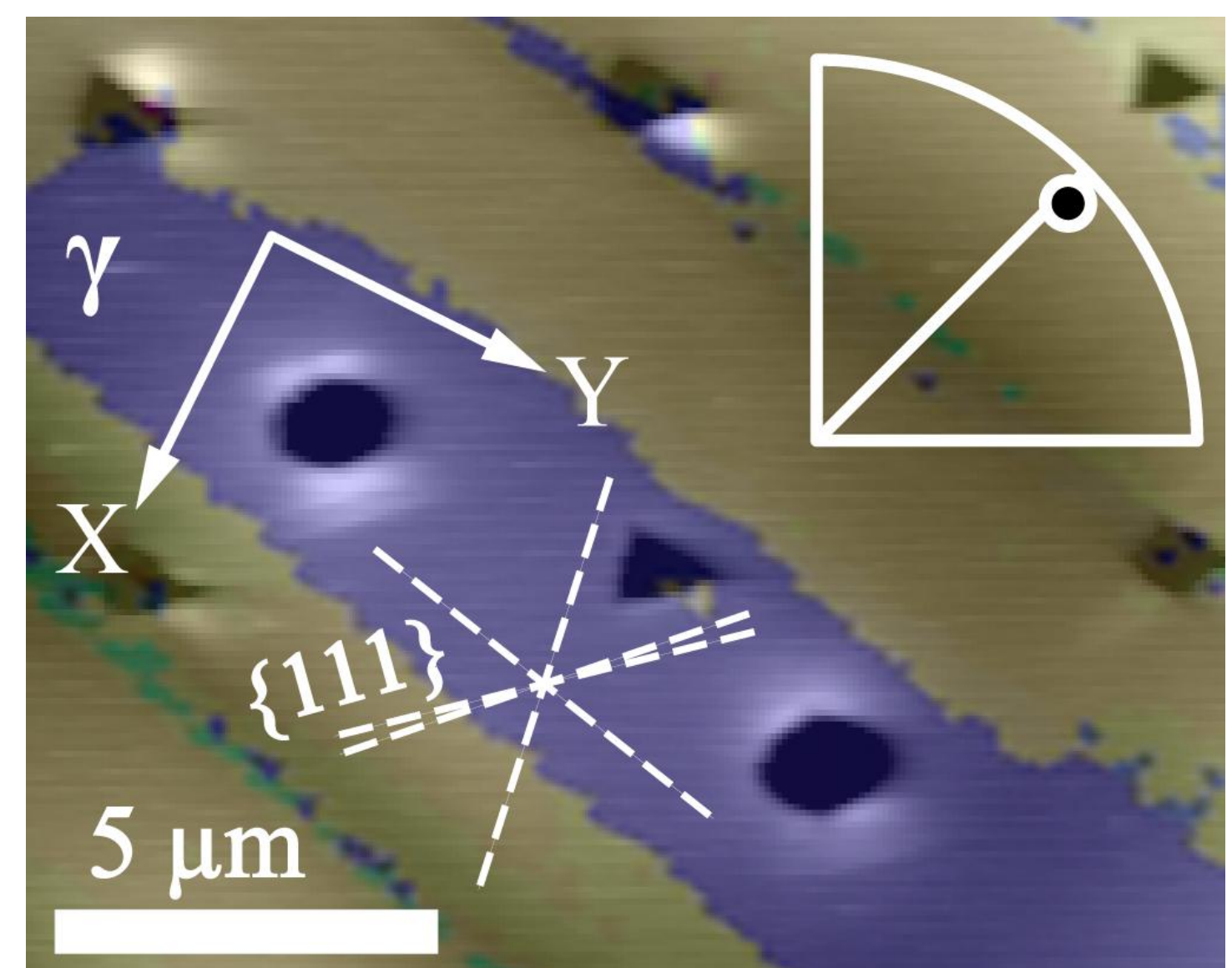
Piling-up and sinking-in is a common phenomenon during indentation of single crystals and polycrystals and can affect the contact area significantly.



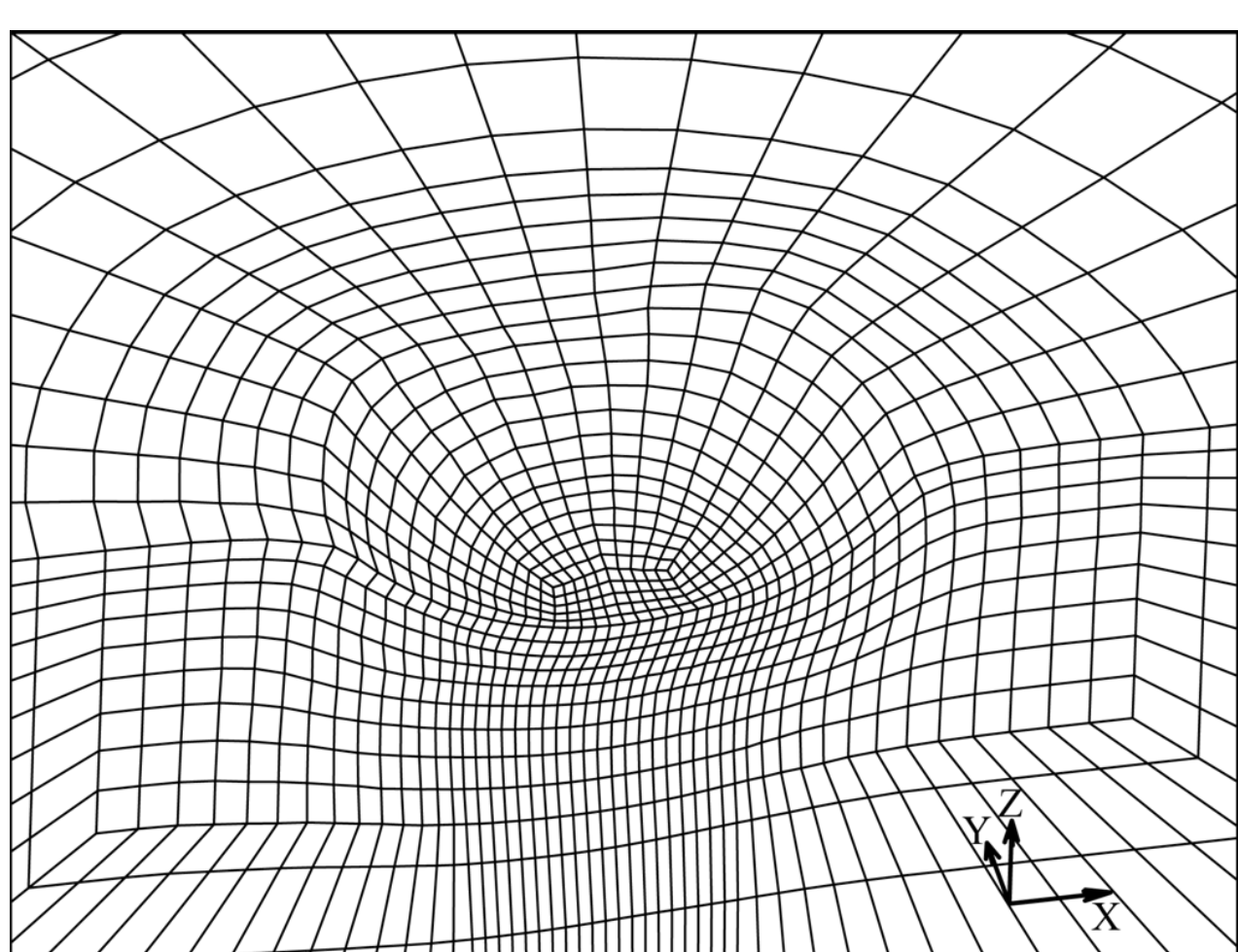
EBSD map and BSE image of a two-phase γ -TiAl based microstructure with indents.



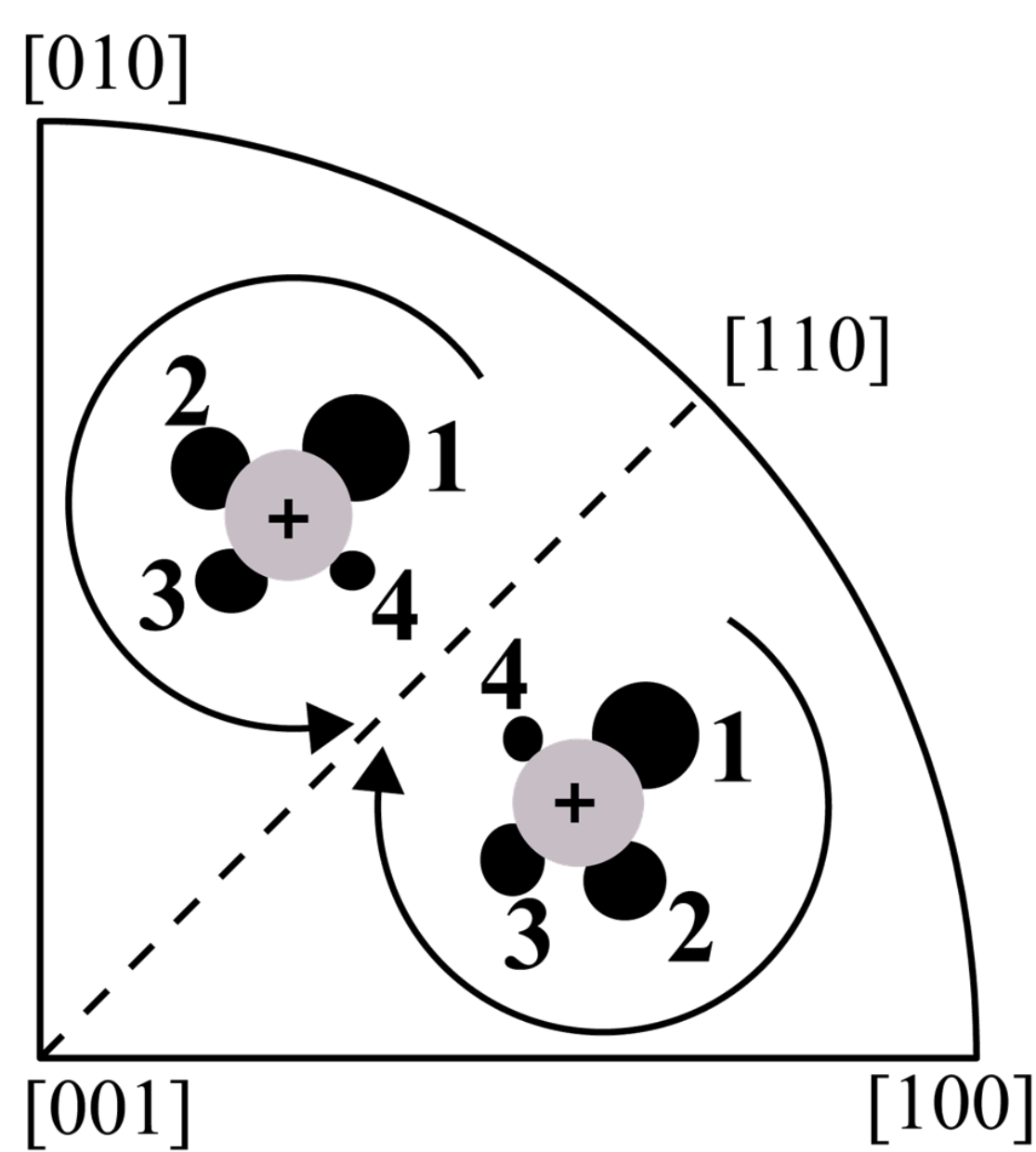
AFM characterization of the indent topography reveals the characteristic pile-up profiles of specific orientations.



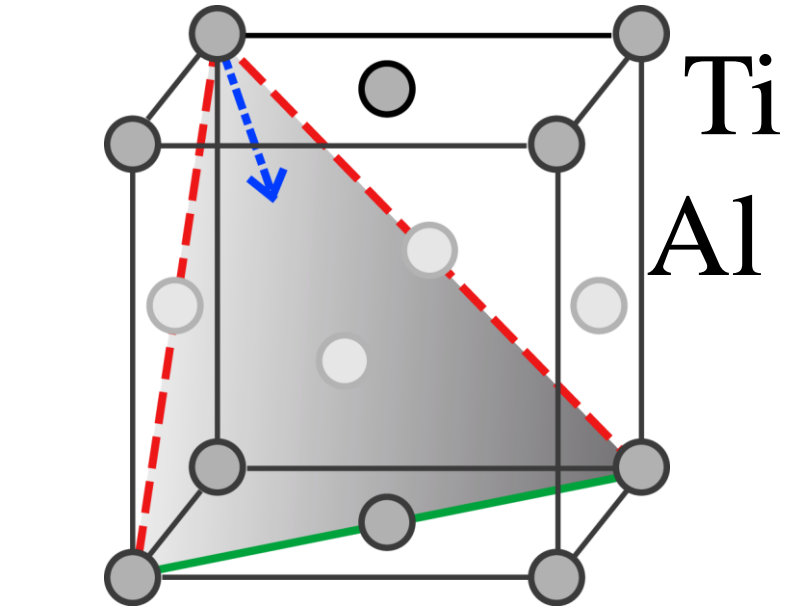
Pile-up patterns from single crystal indentation are known since more than 100 years: a page from Osmond & Cartaud's work on iron in 1906.



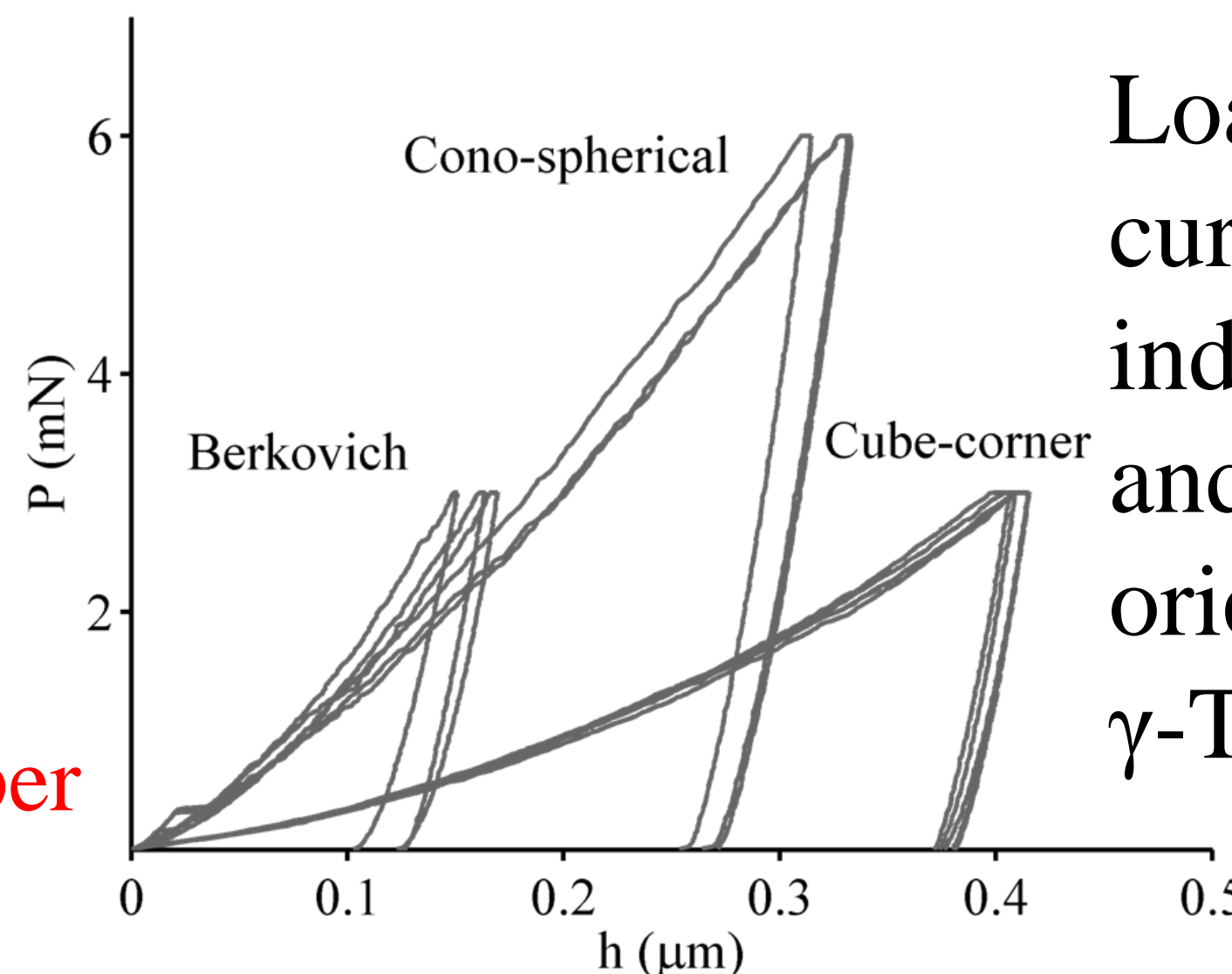
Discretization of the indentation process into 15060 hexahedral finite elements.



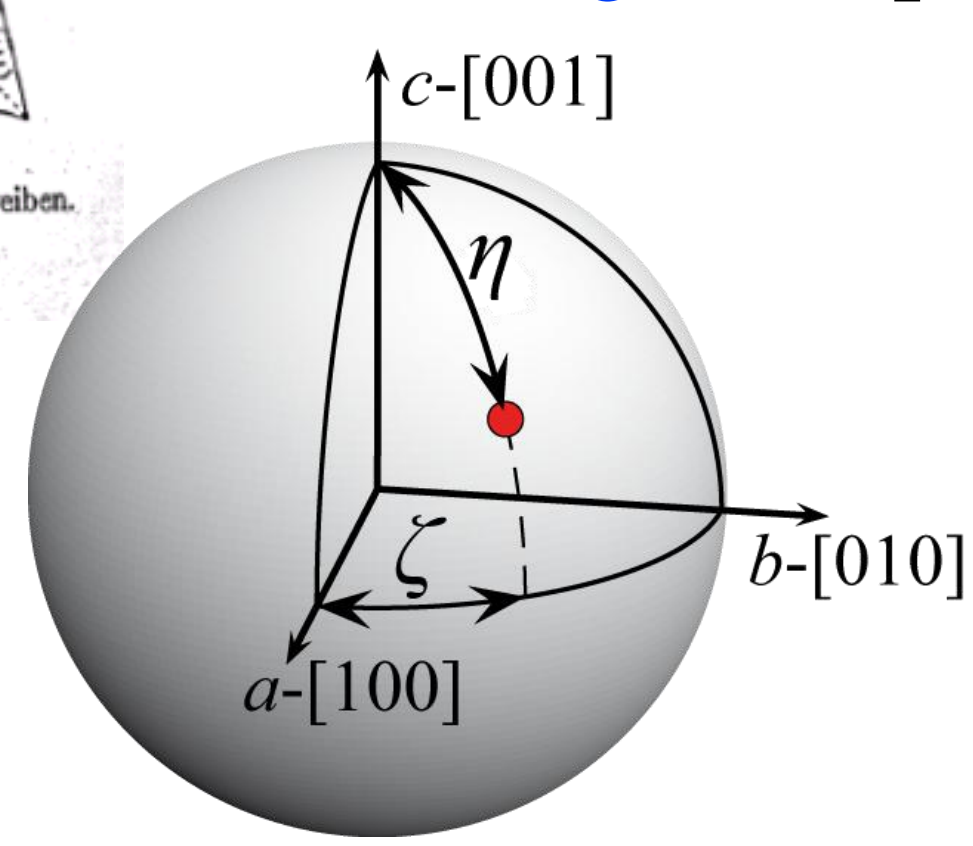
While scalar quantities, such as the unidirectional stiffness, are invariant under an improper symmetry operation acting on the crystal, the pile-up changes its handedness. This holds for any crystal structure.



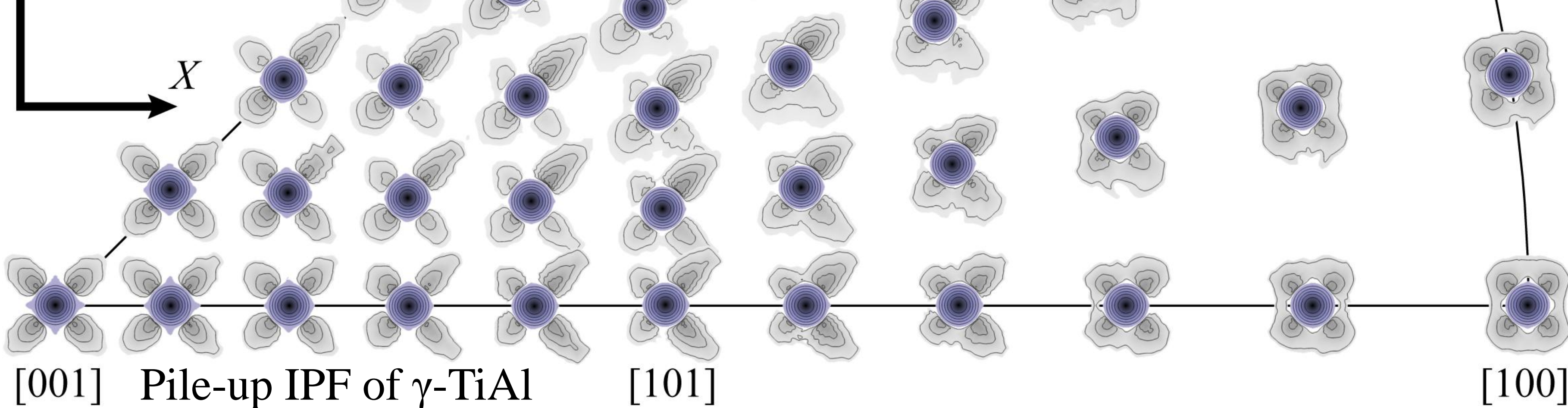
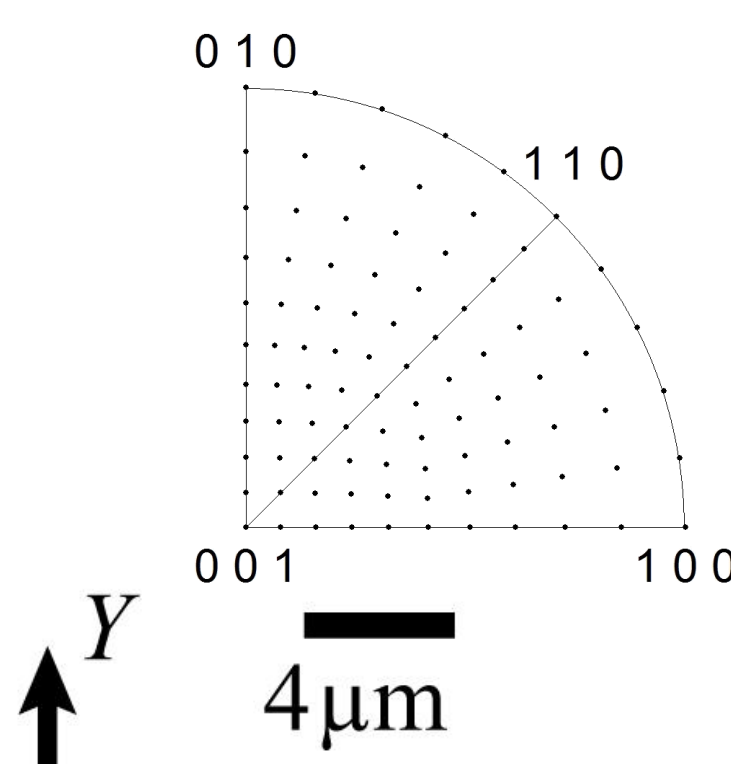
The fcc-derived $L1_0$ structure of γ -TiAl; Ordinary/super dislocation glide and twinning can operate.



Load-displacement curves for different indenter geometries and different orientations of γ -TiAl.

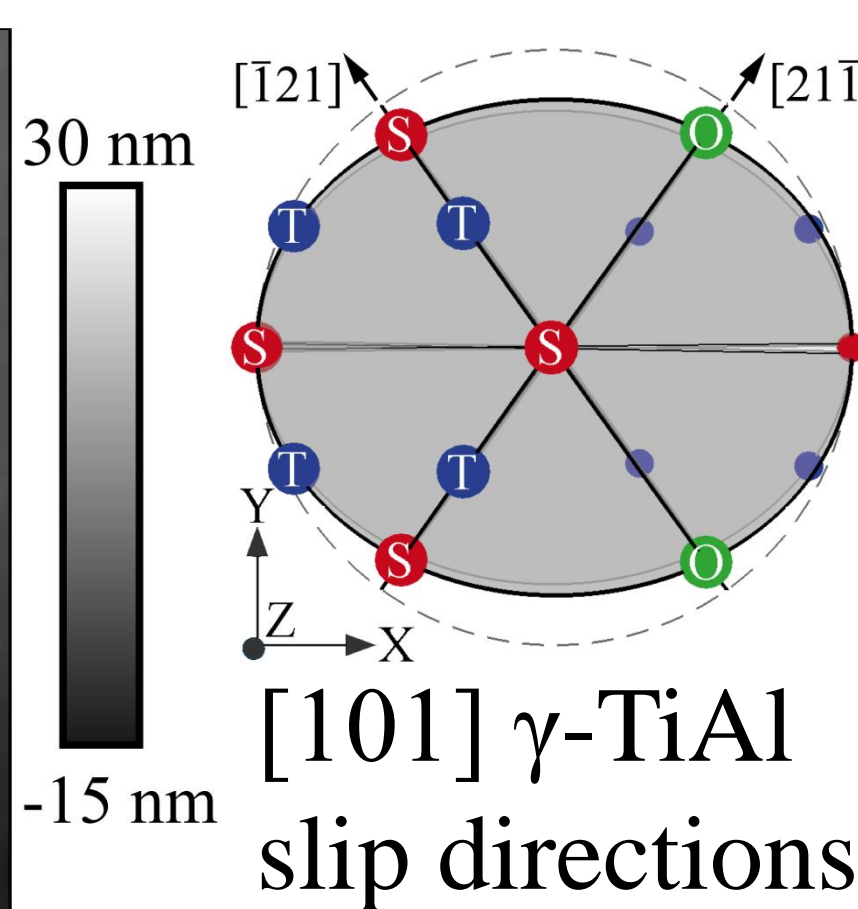
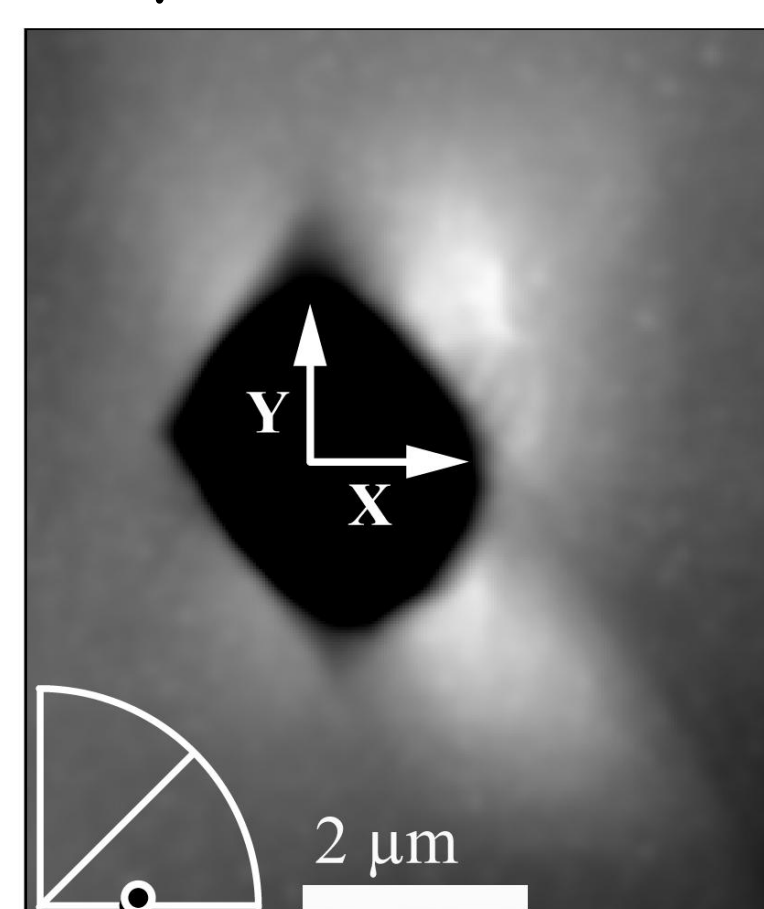


The in-plane orientation convention used in the pile-up IPF.

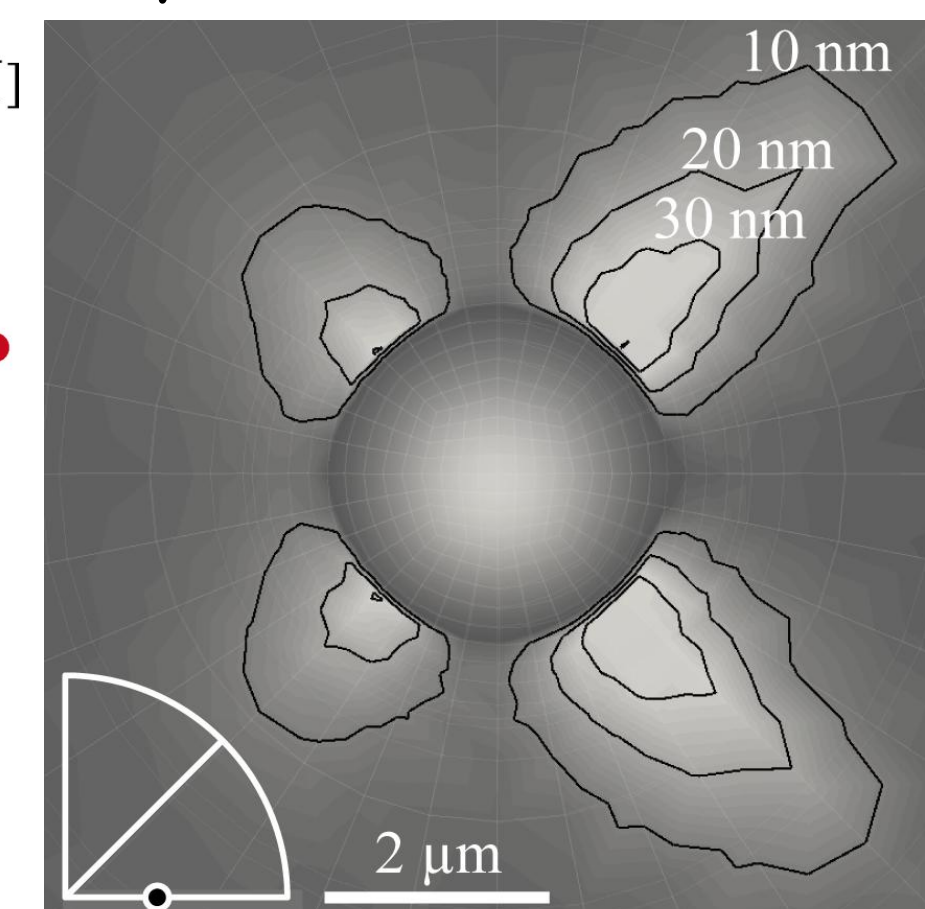


The *inverse pole figure of pileup patterns* was developed, based on a in-plane orientation convention and the representation of pile-up topographies at the stereographic projection of their indentation axis in the inverse pole figure. This graphical representation of the orientation dependent pile-up behavior can be used for any crystal structure indented with tools of arbitrary -- but preferably axisymmetric -- geometry.

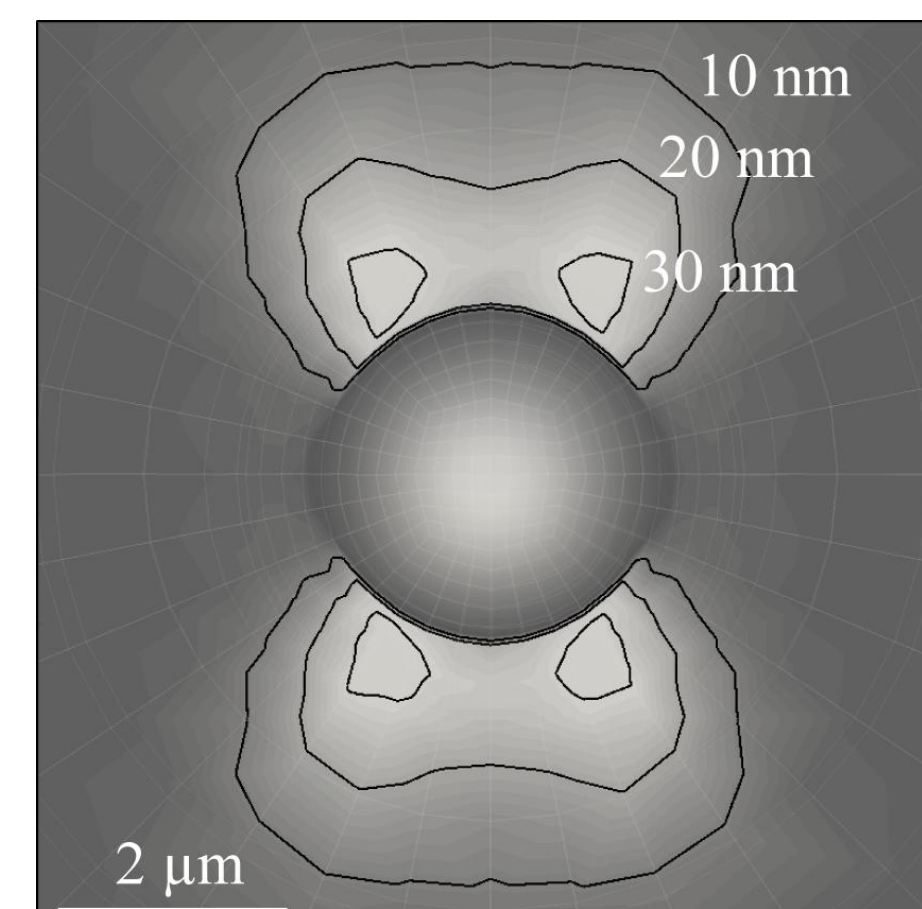
γ -TiAl (AFM)



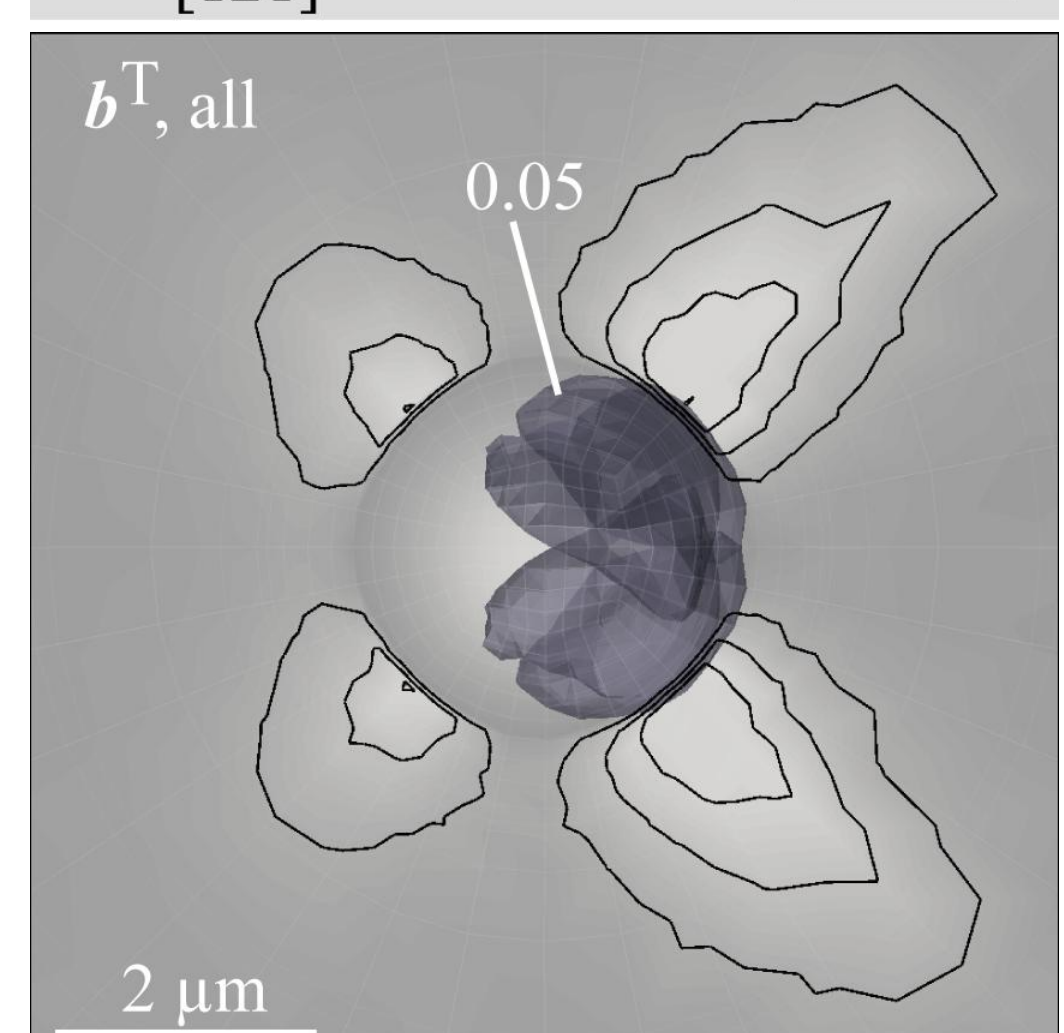
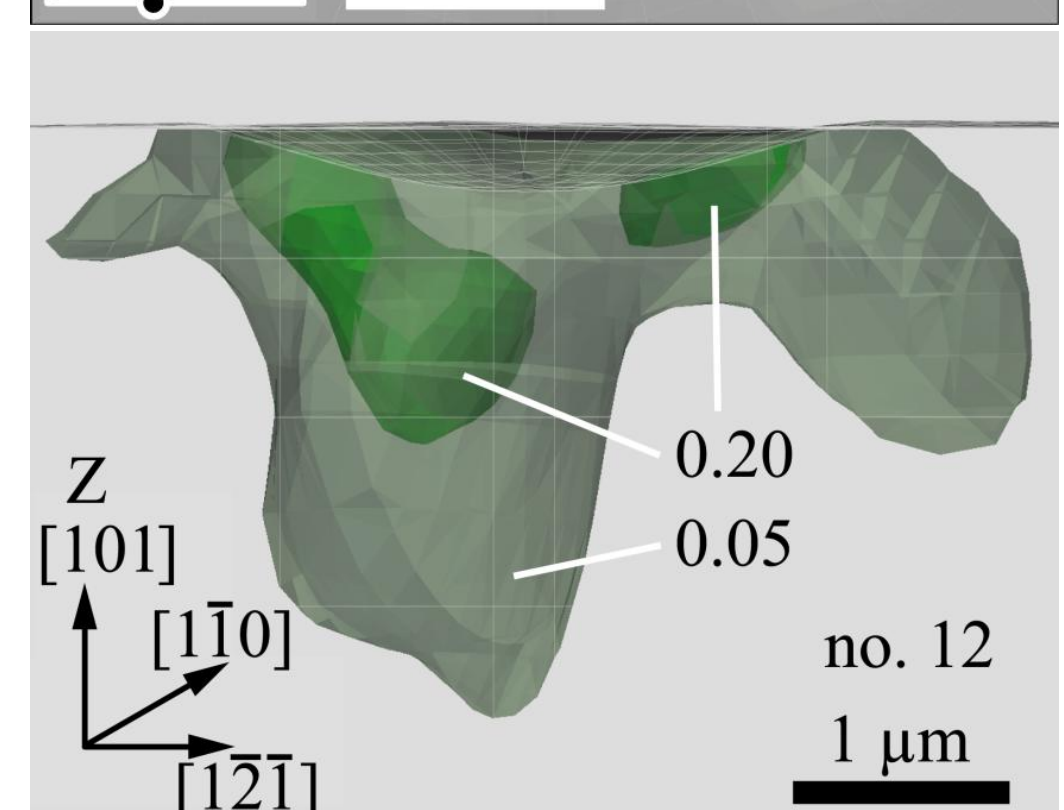
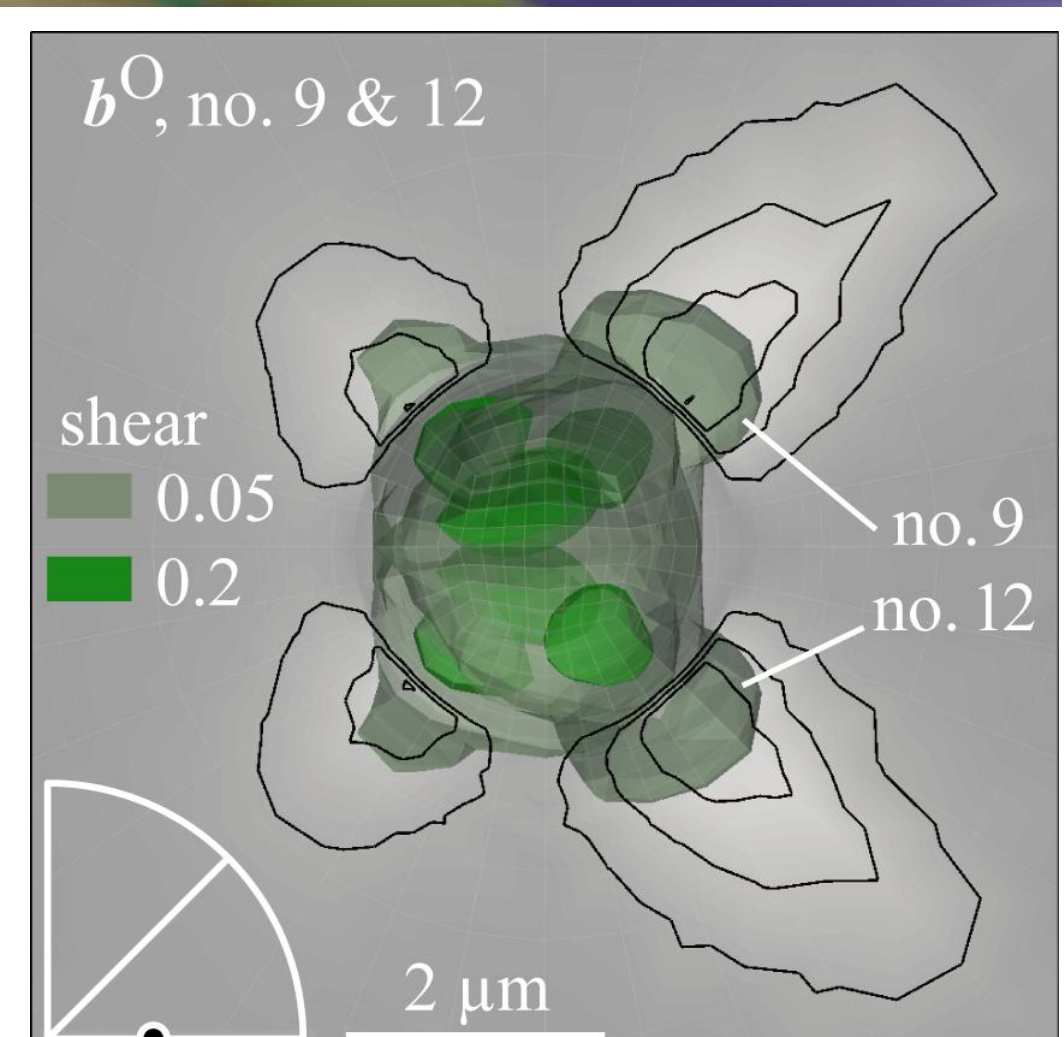
γ -TiAl (CPFEM)



FCC (CPFEM)



The [101] indentation axis was found to be characteristic for the easy activation of ordinary dislocations. In comparison to the known fcc pile-up shape the γ -TiAl pattern exhibits pronounced piling up in the slip directions of ordinary dislocations.



Crystal plasticity finite element simulation of the indentation process can explain the formation of the pile-up patterns based on the activation of different deformation mechanisms.

